

Search Notes

Application/Control No.

10/766,035

Examiner

Jeffrey D. Lane

Applicant(s)/Patent under
Reexamination

ANDO ET AL.

Art Unit

2828

SEARCHED

Class	Subclass	Date	Examiner
372	45.01	5/22/2006	JL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
index of refraction in semiconductor laser	5/22/2006	JL